

## 1<sup>st</sup> International Conference on Helium Ion Microscopy and Emerging Focused Ion Beam Technologies



8 - 10 June 2016 ▶ Luxembourg City

Dear colleague,

We are pleased to announce the 1<sup>st</sup> International Conference on Helium Ion Microscopy and Emerging Focused Ion Beam Technologies (HEFIB 2016) which will be held from 8 to 10 June 2016 in Luxembourg City. The purpose of the conference is to bring together the rapidly growing community active in the fields of Helium Ion Microscopy and other emerging Focused Ion Beam technologies in view of stimulating scientific and technical exchanges.

### Topics

- Helium Ion Microscopy
- Emerging Focused Ion Beam technologies and novel ion sources
- Materials nano-modification and lithography
- Nano-imaging and nano-analytics, including correlative approaches
- Bio-imaging
- Fundamentals and modelling on particle-matter interactions
- Instrument development

The programme will include invited talks, contributed oral presentations, a poster session, and topical round table discussions. Several social events (including an excursion and a conference dinner) will provide room for networking. For more detailed information, please visit the conference website [www.hefib2016.list.lu](http://www.hefib2016.list.lu)

**We are looking forward to seeing you in June 2016 in Luxembourg!**

Best regards,

### The organizing committee

**Tom Wirtz**, Luxembourg Institute of Science and Technology, Luxembourg

**Paul Alkemade**, Delft University of Technology, The Netherlands

**Armin Gölzhäuser**, University of Bielefeld, Germany

**Gregor Hlawacek**, Helmholtz-Zentrum Dresden-Rossendorf, Germany

**Hongzhou Zhang**, Trinity College Dublin, Ireland

### IMPORTANT DATES

- ▶ Call for papers:  
January 2016
- ▶ Deadline for abstract  
submission:  
4 April 2016



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